









SN54HC563, SN74HC563 SCLS145E - DECEMBER 1982 - REVISED JULY 2022

SNx4HC563 Octal Transparent D-Type Lataches With 3-State Outputs

1 Features

- Wide operating voltage range of 2 V to 6 V
- High-current 3-state outputs drive bus lines directly or up to 15 LSTTL loads
- Lowpower consumption, 80-µA max I_{CC}
- Typical t_{pd} = 21 ns
- ±6-mA output drive at 5 V
- Low input current of 1 µA max
- **Bus-structured** pinout

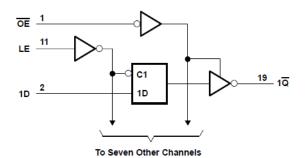
2 Description

These 8-bit transparent D-type latches feature 3state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

Device Information

PART NUMBER	PACKAGE ⁽¹⁾	BODY SIZE (NOM)				
SN74HC563DW	SOIC (20)	12.80 mm × 7.50 mm				
SN74HC563N	PDIP (20)	25.40 mm × 6.35 mm				

For all available packages, see the orderable addendum at the end of the data sheet.



Functional Block Diagram



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3 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision D (January 2022) to Revision E (July 2022)

Page

Junction-to-ambient thermal resistance values increased. DW was 58 is now 109.1, N was 69 is now 84.6....4

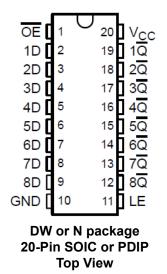
Changes from Revision C (March 2003) to Revision D (January 2022)

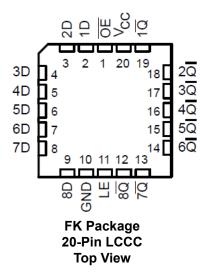
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4 Pin Configuration and Functions





5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V _{CC}	Supply voltage range		-0.5	7	V
I _{IK}	Input clamp current ⁽²⁾	$V_I < 0 \text{ or } V_I > V_{CC}$		±20	mA
I _{OK}	Output clamp current ⁽²⁾	$V_O < 0$ or $V_O > V_{CC}$		±20	mA
Io	Continuous output current	$V_O = 0$ to V_{CC}		±35	mA
	Continuous current through V _{CC} or GND	·		±70	mA
TJ	Junction temperature			150	°C
T _{stg}	Storage temperature range		-65	150	°C

¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

5.2 Recommended Operating Conditions(1)

			SN	54HC563		SN	74HC563		UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
V _{CC}	Supply voltage		2	5	6	2	5	6	V
		V _{CC} = 2 V	1.5			1.5			
V_{IH}	High-level input voltage	V _{CC} = 4.5 V	3.15			3.15			V
		V _{CC} = 6 V	4.2			4.2			
		V _{CC} = 2 V			0.5			0.5	
V _{IL}	Low-level input voltage	V _{CC} = 4.5 V			1.35			1.35	V
	Low-level input voltage	V _{CC} = 6 V			1.8			1.8	
VI	Input voltage		0		V _{CC}	0		V _{CC}	V
Vo	Output voltage		0		V _{CC}	0		V _{CC}	V
		V _{CC} = 2 V			1000			1000	
t _t	Input transition (rise and fall) time	V _{CC} = 4.5 V			500			500	ns
		V _{CC} = 6 V			400			400	
T _A	Operating free-air temperature	·	– 55		125	-40		85	°C

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

5.3 Thermal Information

		DW (SOIC)	N (PDIP)	
THERMAL ME	ETRIC	20 PINS	20 PINS	UNIT
R _{θJA}	Junction-to-ambient thermal resistance ⁽¹⁾	109.1	84.6	°C/W
R _{0JC (top)}	Junction-to-case (top) thermal resistance	76	72.5	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	77.6	65.3	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	51.5	55.3	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	77.1	65.2	°C/W
R _{0JC (bot)}	Junction-to-case (bottom) thermal resistance	N/A	N/A	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC package thermal metrics application report.

⁽²⁾ The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



5.4 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CO	NDITIONS	V _{cc}	T,	_A = 25°C		SN54H0	C563	SN74H0	C563	UNIT
PARAMETER	1231 00	NDITIONS	V CC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
			2 V	1.9	1.998		1.9		1.9		
		I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
V_{OH}	$V_I = V_{IH}$ or V_{IL}		6 V	5.9	5.999		5.9		5.9		V
		I _{OH} = -6 mA	4.5 V	3.98	4.3		3.7		3.84		
		$I_{OH} = -7.8 \text{ mA}$	6 V	5.48	5.8		5.2		5.34		
	V _I = V _{IH} or V _{IL}		2 V		0.002	0.1		0.1		0.1	
		I _{OL} = 20 μA	4.5 V		0.001	0.1		0.1		0.1	
V_{OL}			6 V		0.001	0.1		0.1		0.1	V
		I _{OL} = 6 mA	4.5 V		0.17	0.26		0.4		0.33	
		I _{OL} = 7.8 mA	6 V		0.15	0.26		0.4		0.33	
I _I	$V_I = V_{CC}$ or 0	V _{CC} or 0			±0.1	±100		±1000		±1000	nA
l _{oz}	$V_O = V_{CC}$ or 0	V _{CC} or 0			±0.01	±0.5		±10		±5	μA
I _{CC}	$V_I = V_{CC}$ or 0,	I _O = 0	6 V			8		160		80	μA
C _i			2 V to 6 V		3	10		10		10	pF

5.5 Timing Requirements

over recommended operating free-air temperature range (unless otherwise noted)

	innonaca speranng nee an ien		T _A = 25°		SN54HC	563	SN74HC	563	UNIT
		V _{CC}	MIN	MAX	MIN	MAX	MIN	MAX	UNII
		2 V	80		120		100		
t _w	Pulse duration, LE high	4.5 V	16		24		20		ns
		6 V	14		20		17		
		2 V	50		75		63		ns
t _{su}	Setup time, data before LE↓	4.5 V	10		15		13		
		6 V	9		13		11		
		2 V	5		5		5		
t _h	Hold time, data after LE↓	4.5 V	5		5		5		ns
		6 V	5		5		5		



5.6 Switching Characteristics

over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Parameter Measurement Information)

PARAMETER	FROM	то	V	T _A =	= 25°C		SN54HC563		SN74HC56	3	UNIT											
PARAMETER	(INPUT)	(OUTPUT)	V _{cc}	MIN	TYP	MAX	MIN M	AX	MIN	MAX	UNIT											
			2 V		77	175	2	265		220												
	D	Q	4.5 V		26	35		53		44												
t _{pd}			6 V		23	30		45		37	no											
	t _{pd} LE		2 V		90	175	2	265		220	ns											
		Any Q	4.5 V		27	35		53		44												
			6 V		23	30		45		37												
			2 V		70	150	2	225		190												
t _{en}	ŌĒ	ŌĒ	ŌĒ	ŌĒ	ŌĒ	ŌĒ	ŌĒ	ŌĒ	ŌĒ	ŌĒ	ŌĒ	ŌĒ	DE Any Q	4.5 V		24	30		45		38	ns
			6 V		21	26		38		32												
			2 V		47	150	2	225		190												
t_{dis}	ŌĒ	Any Q	4.5 V		23	30		45		38	ns											
			7, Q	7, Q	,, Q	7, Q	, 🗨	, Q	6 V		21	26		38		32						
		Any Q	2 V		28	60		90		75												
t _t			4.5 V		8	12		18		15	ns ns											
			6V		6	10		15		13												

5.7 Switching Characteristics

over recommended operating free-air temperature range, $C_L = 150 \text{ pF}$ (unless otherwise noted) (see Parameter Measurement Information)

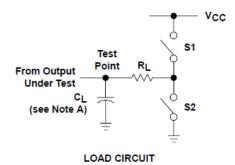
PARAMETER	FROM	то	V	TA	= 25°C		SN54HC	563	SN74HC	563	UNIT					
PARAMETER	(INPUT)	(OUTPUT)	V _{CC}	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII					
			2 V		95	200		300		250						
t _{pd} –	D	Q	4.5 V		33	40		60		50						
			6 V		29	34		51		43	ns					
	LE		2 V		103	225		335		285	115					
		Any \overline{Q}	4.5 V		33	45		67		57						
			6 V		29	38		57		48						
			2 V		85	200		300		250						
t _{en}	ŌĒ	Any Q	Any Q	Any Q	Any Q	Any Q	Any Q	4.5 V		29	40		60		50	ns
				6 V		26	34		51		43					
			2 V		60	210		315		265						
t _t		Any Q 4.5	4.5 V		17	42		63		53	ns					
			6 V		14	36		53		45						

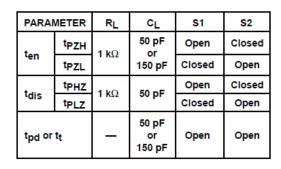
5.8 Operating Characteristics

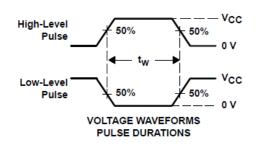
T_A = 25°C

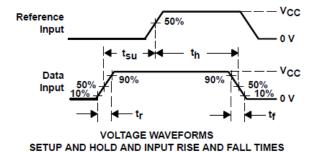
	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per latch	No load	50	pF

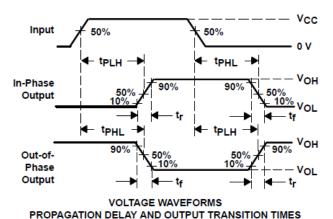
6 Parameter Measurement Information

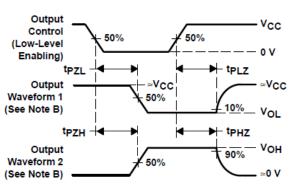












VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

- A. C₁ includes probe and test-fixture capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_r = 6 \text{ ns}$, $t_f = 6 \text{ ns}$.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 6-1. Load Circuit and Voltage Waveforms

7 Detailed Description

7.1 Overview

These 8-bit transparent D-type latches feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

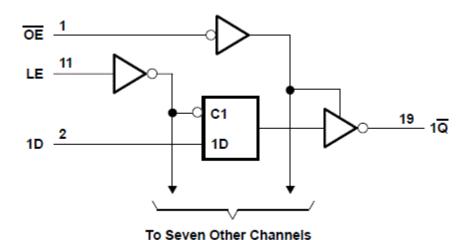
While the latch-enable (LE) input is high, the Q outputs follow the complements of the data (D) inputs. When LE is taken low, the outputs are latched at the inverses of the levels set up at the D inputs.

A buffered output-enable (\overline{OE}) input places the eight outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased high logic level provide the capability to drive bus lines without interface or pullup components.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to VCC through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

OE does not affect internal operations of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

7.2 Functional Block Diagram



7.3 Device Functional Modes

Table 7-1. Function Table (Each Latch)

	INPUTS								
ŌĒ	LE	D	Q						
L	Н	Н	L						
L	Н	L	Н						
L	L	Х	Q ₀						
Н	Х	Х	Z						



8 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A 0.1-µF capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1-µF and 1-µF capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

9 Layout

9.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC} , whichever makes more sense for the logic function or is more convenient.

10 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

10.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

10.2 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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10.3 Trademarks

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10.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
SN74HC563DW	OBSOLETE	SOIC	DW	20		TBD	Call TI	Call TI	-40 to 85	HC563	
SN74HC563DWR	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HC563	Samples
SN74HC563N	ACTIVE	PDIP	N	20	20	RoHS & Green	NIPDAU	N / A for Pkg Type	-40 to 85	SN74HC563N	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE OPTION ADDENDUM

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

www.ti.com 12-May-2023

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74HC563DWR	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1

PACKAGE MATERIALS INFORMATION

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74HC563DWR	SOIC	DW	20	2000	367.0	367.0	45.0

PACKAGE MATERIALS INFORMATION

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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
SN74HC563N	N	PDIP	20	20	506	13.97	11230	4.32

N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.





SOIC



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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